

Second edition
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**Preparation of steel substrates before
application of paints and related
products — Surface roughness
characteristics of blast-cleaned steel
substrates —**

**Part 3:
Method for the calibration of ISO
surface profile comparators and for
the determination of surface profile —
Focusing microscope procedure**

*Préparation des sujets d'acier avant application de peintures et
de produits assimilés — Caractéristiques de rugosité des sujets
d'acier décapés —*

*Partie 3: Méthode d'étalonnage des comparateurs viso-tactiles ISO et de
classification d'un profil de surface — Utilisation d'un microscope optique*

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